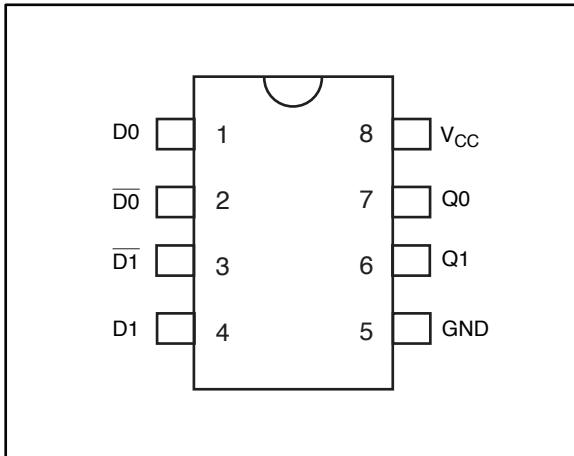




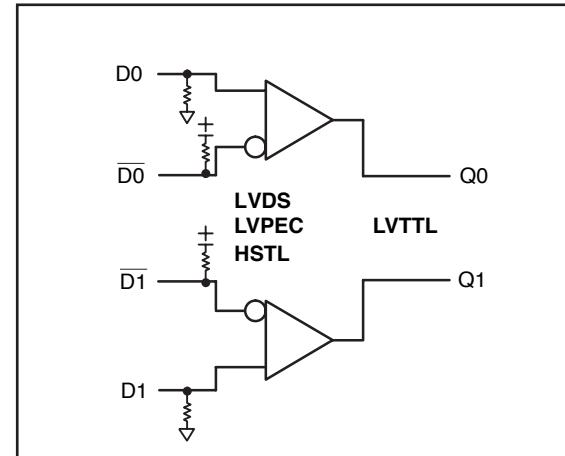
## Dual Differential LVDS/LVPECL/HSTL to LVTTL Translator

FEATURES:	DESCRIPTION:
<ul style="list-style-type: none"> <li>Patented Technology</li> <li>Differential LVDS/LVPECL/HSTL to LVTTL Translator</li> <li>Operating frequency up to 1GHz with 2pf load</li> <li>Operating frequency up to 800MHz with 5pf load</li> <li>Operating frequency up to 450MHz with 15pf load</li> <li>Very low output pin to pin skew &lt; 150ps</li> <li>Propagation delay &lt; 1.8ns max with 15pf load</li> <li>2.4V to 3.6V power supply</li> <li>Industrial temperature range: -40°C to 85°C</li> <li>Available in 8-pin SOIC package</li> <li>Available in 8-pin TSSOP package</li> </ul>	<p>Potato Semiconductor's PO100HSTL23A is designed for world top performance using submicron CMOS technology to achieve 1GHz LVTTL output frequency with less than 1.8ns propagation delay.</p> <p>The PO100HSTL23A is a low-skew, The small outline 8 pin package and the low skew design to make it ideal for applications which require the translation of a clock or a data signal.</p>

### Pin Configuration



### Logic Block Diagram



### Pin Description

Pin	Function
Q0, Q1	LVTTL Outputs
D0, D1 D0-bar, D1-bar	Differential LVDS/LVPECL/HSTL Inputs
V <sub>CC</sub>	Positive Supply
GND	Ground

## Dual Differential LVDS/LVPECL/HSTL to LVTTL Translator

### Maximum Ratings

Description	Max	Unit
Storage Temperature	-65 to 150	°C
Operation Temperature	-40 to 85	°C
Operation Voltage	-0.5 to +4.6	V
Input Voltage	-0.5 to Vcc	V
Output Voltage	-0.5 to Vcc+0.5	V

#### Note:

stresses greater than listed under Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability specification is not implied.

### Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$C_{IN}$	Input Capacitance			4		pF
$R_{PULLUP}$	Input Pullup Resistor			88		kΩ
$R_{PULLDOWN}$	Input Pulldown Resistor			88		kΩ

### DC Electrical Characteristics

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
$V_{OH}$	Output High voltage	$Vcc=3V$ $Vin=VIH$ or $VIL$ , $IOH=-12mA$	<b>2.4</b>	<b>3</b>	-	V
$V_{OL}$	Output Low voltage	$Vcc=3V$ $Vin=VIH$ or $VIL$ , $IOH=12mA$	-	<b>0.3</b>	<b>0.5</b>	V
$VIH$	Input High voltage	Guaranteed Logic HIGH Level (Input Pin)	<b>2</b>	-	$Vcc$	V
$VIL$	Input Low voltage	Guaranteed Logic LOW Level (Input Pin)	<b>-0.5</b>	-	<b>0.8</b>	V
$I_{IH}$	Input High current	$Vcc = 3.6V$ and $Vin = Vcc$	-	-	<b>1</b>	uA
$I_{IL}$	Input Low current	$Vcc = 3.6V$ and $Vin = 0V$	-	-	<b>-1</b>	uA
$VIK$	Clamp diode voltage	$Vcc = \text{Min. And } I_{IN} = -18mA$	-	<b>-0.7</b>	<b>-1.2</b>	V

#### Notes:

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at  $Vcc = 3.3V$ ,  $25^{\circ}\text{C}$  ambient.
3. This parameter is guaranteed but not tested.
4. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.
5.  $VoH = Vcc - 0.6V$  at rated current



## Dual Differential LVDS/LVPECL/HSTL to LVTTL Translator

### Power Supply Characteristics

Symbol	Description	Test Conditions (1)	Min	Typ	Max	Unit
<b>I<sub>CCQ</sub></b>	Quiescent Power Supply Current	V <sub>CC</sub> =Max, V <sub>IN</sub> =V <sub>CC</sub> or GND	-	<b>0.1</b>	<b>30</b>	<b>uA</b>

**Notes:**

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at V<sub>CC</sub> = 3.3V, 25°C ambient.
3. This parameter is guaranteed but not tested.
4. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.

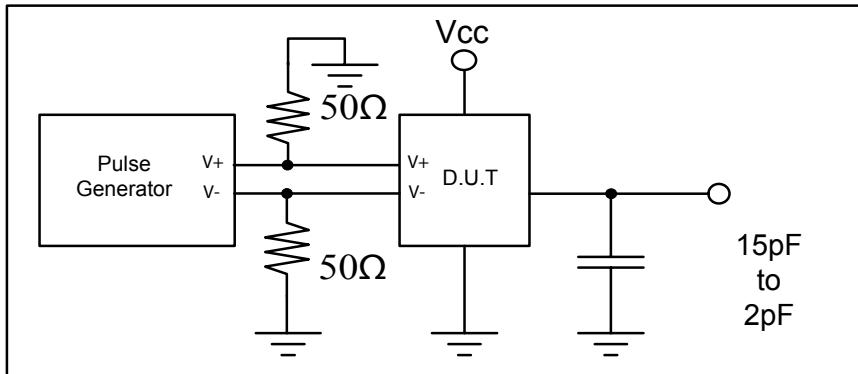
### Switching Characteristics

Symbol	Description	Test Conditions (1)	Max	Unit
<b>t<sub>PD</sub></b>	Propagation Delay D to Output pair	CL = 15pF	<b>1.8</b>	<b>ns</b>
<b>tr/tf</b>	Rise/Fall Time	0.8V – 2.0V	<b>0.8</b>	<b>ns</b>
<b>tsk(o)</b>	Output Pin to Pin Skew (Same Package)	CL = 15pF, 125MHz	<b>150</b>	<b>ps</b>
<b>tsk(pp)</b>	Output Skew (Different Package)	CL = 15pF, 125MHz	<b>300</b>	<b>ps</b>
<b>f<sub>max</sub></b>	Input Frequency	CL = 15pF	<b>450</b>	<b>MHz</b>
<b>f<sub>max</sub></b>	Input Frequency	CL = 5pF	<b>800</b>	<b>MHz</b>
<b>f<sub>max</sub></b>	Input Frequency	CL = 2pF	<b>1000</b>	<b>MHz</b>

**Notes:**

1. See test circuits and waveforms.
2. t<sub>PLH</sub>, t<sub>PHL</sub>, t<sub>sk(p)</sub>, and t<sub>sk(o)</sub> are production tested. All other parameters guaranteed but not production tested.
3. Airflow of 1m/s is recommended for frequencies above 133MHz

### Test Circuit

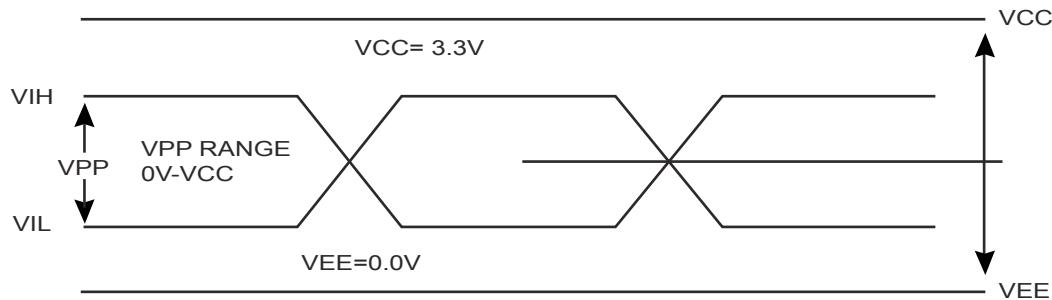




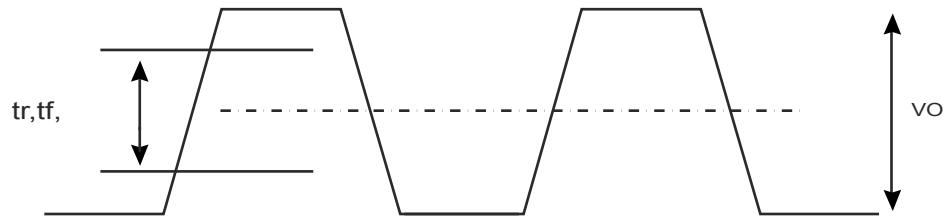
## Dual Differential LVDS/LVPECL/HSTL to LVTTL Translator

### Test Waveforms

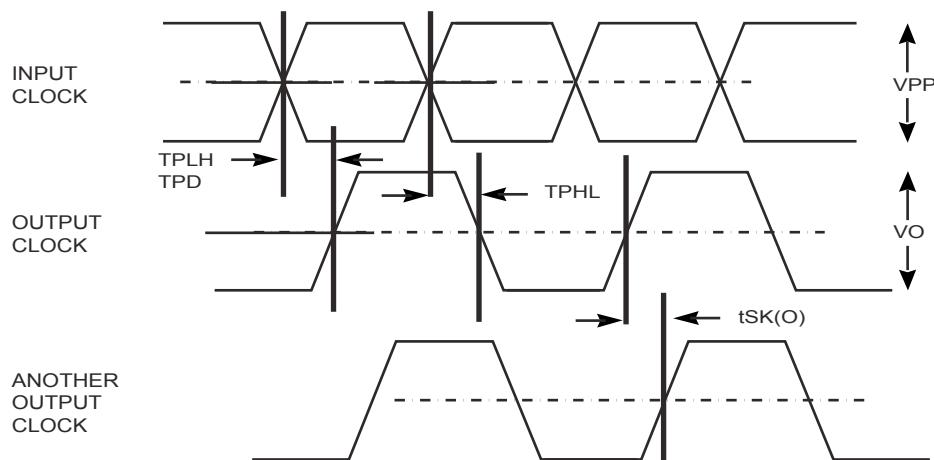
**FIGURE 1.**  
**LVDS/ PECL/ ECL/ HSTL /DIFFERENTIAL INPUT WAVEFORM DEFINITIONS**



**FIGURE 2.**  
**LVTTL OUTPUT**



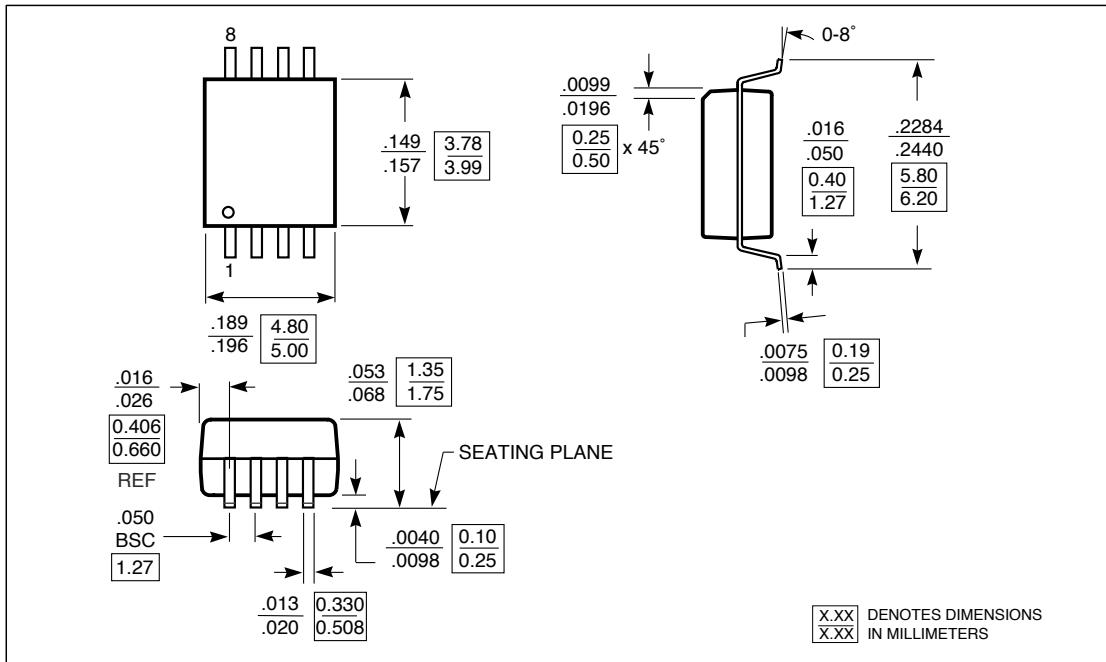
**FIGURE 3.**  
**Propagation Delay, Output pulse skew, and output-to-output skew for D to output**



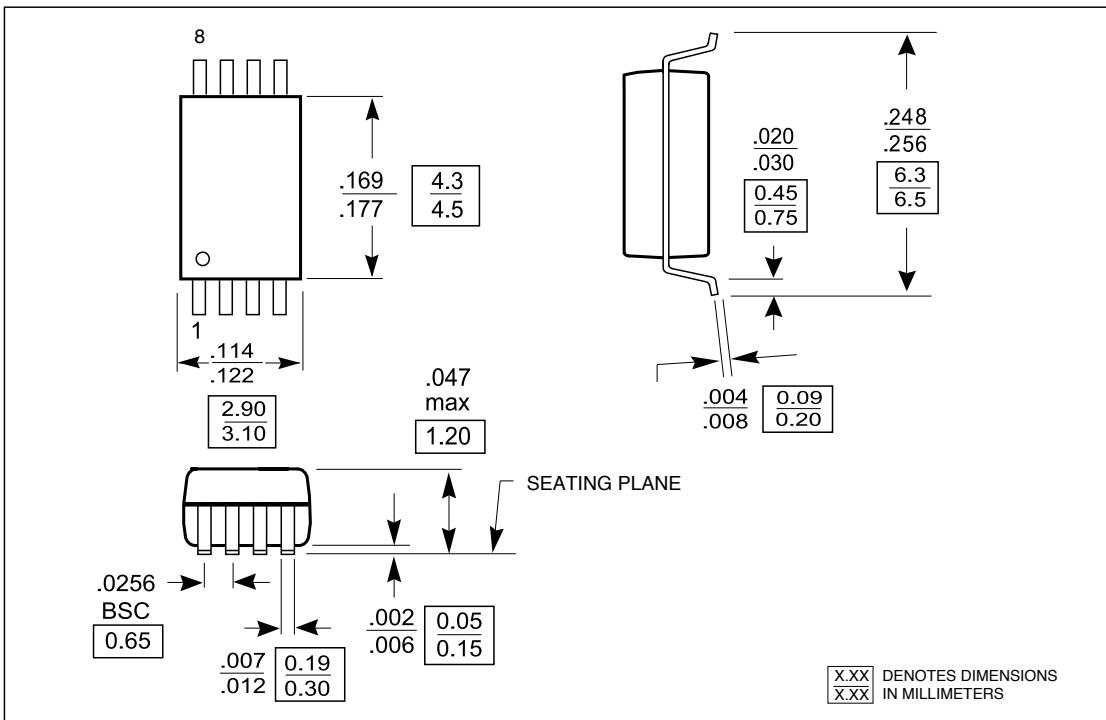


## Dual Differential LVDS/LVPECL/HSTL to LVTTL Translator

### Packaging Mechanical Drawing: 8 pin SOIC



### Packaging Mechanical Drawing: 8 pin TSSOP



## Dual Differential LVDS/LVPECL/HSTL to LVTTL Translator

### Ordering Information

Ordering Code	Package			Top-Marking	TA
PO100HSTL23ASU	8 pin SOIC	Tube	Pb-free & Green	PO100HSTL23AS	-40°C to 85°C
PO100HSTL23ASR	8 pin SOIC	Tape and reel	Pb-free & Green	PO100HSTL23AS	-40°C to 85°C
PO100HSTL23ATU	8 pin TSSOP	Tube	Pb-free & Green	PO100HSTL23AT	-40°C to 85°C
PO100HSTL23ATR	8 pin TSSOP	Tape and reel	Pb-free & Green	PO100HSTL23AT	-40°C to 85°C